

Contents

1	Introduction	1
2	Theoretical Background	5
2.1	Solar cell physics	5
2.1.1	Semiconductor physics and operation principle	6
2.1.2	Recombination mechanisms and injection conditions	12
2.1.3	Diode models and I-V curve analysis	22
2.1.4	Peltier effect	26
2.2	IBC solar cell design and current flow	29
2.3	Physical principles of applied imaging techniques	37
2.3.1	Luminescence imaging	37
2.3.2	Lock-in thermography	42
3	SR-LBIC for short-circuit current density mapping	51
3.1	Literature overview	52
3.2	Experimental setup and spatial resolution	54
3.3	J_{sc}^{loc} -mapping principle	56
3.4	Pseudo- J_{sc}^{loc} and optical loss mapping	61
3.5	Quantified local J_{sc} losses in IBC cells	64
4	Luminescence imaging of local cell characteristics	71
4.1	Literature overview	72

4.2	Experimental setup and spatial resolution	75
4.3	Interpretation of luminescence patterns and contrasts	80
4.3.1	PL: Luminescence imaging under illumination	80
4.3.2	EL: Luminescence imaging in the dark	85
4.4	Numerical modeling of luminescence images	90
4.4.1	Luminescence intensity and optical blurring . .	92
4.4.2	Example simulation results	97
4.5	Surface recombination parameters from modeled lumi- nescence images	101
4.5.1	Sensitivity analysis	101
4.5.2	Matching experiments with simulation data . .	105
4.6	Local series resistance imaging	109
4.6.1	Definition, voltage calibration and image inter- pretation	109
4.6.2	Lateral transport effects	116
5	Lock-in thermography of local cell characteristics	121
5.1	Literature overview	122
5.2	Experimental setup, emissivity and spatial resolution .	125
5.3	Local power dissipation and Peltier effect modeling . .	130
5.3.1	Simulation model	131
5.3.2	Modeling results and consequences for LIT . .	138
5.4	Heat sources, power calibration and contrast patterns	148
6	Detection of local processing faults	161
6.1	Literature overview	162
6.2	Local series resistance faults	166
6.2.1	Simulated I-V and luminescence characteristics	166
6.2.2	Experimental verification	178
6.3	Local shunting faults	187
6.3.1	Pinholes	187
6.3.2	Spikes	194
6.4	Optical and passivation faults	204

6.5 Breakdown patterns	208
7 Discussion and guidelines for IBC cell characteriza-	
tion	215
7.1 Guidelines for pattern and contrast interpretation . . .	216
7.2 Guidelines for identification of local processing faults .	223
7.3 Review and limitations of the proposed methods . . .	236
8 Summary and outlook	243
Ausführliche Zusammenfassung in deutscher Sprache	251
A Details on all investigated solar cells	259
Bibliography	262
List of symbols, abbreviations and physical constants	295
List of publications	305
Acknowledgements	309